Search Notes				

Application/Control No.	Applicant(s)/Patent under Reexamination
10/695,681	CHEN ET AL.
Examiner	Art Unit
Yicun Wu	2165

SEARCHED					
Class	Subclass	Date	Examiner		
707	1-10, 100- 104.1 200-206	6/5/2006	ΥW		
705	26	6/5/2006	YW		
upolated	Search	11/5/06	yw.		
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INTERFERENCE SEARCHED  Class Subclass Date Examine					
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707	2,3,4,6	11/5/06	yw		

SEARCH NO (INCLUDING SEARCH		)
	DATE	EXMR
inventor search (double patenting) uspto uspgpub epo jpo ibmtech derwent	6/5/2006	YW.
acm ieee citeseer internet Search stratagy attached	6/5/2006	YW
consulted Apu Mofiz	6/5/2006	ΥW
updated sparch	11/5/00	'yw
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